

<b>Notice of References Cited</b>	Application/Control No. 08/840,947	Applicant(s)/Patent Under Reexamination LIU, EDWARD W.	
	Examiner DINH T. LE	Art Unit 2816	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,038,215	08-1991	HADFIELD	358/150
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP406022007A	01-1994	JAPAN	TANAKA	-
	O	JP61201598A	09-1986	JAPAN	AMAMIYA	-
	P					-
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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